## Search Notes

Search Notes	

Application/Control No.	Applicant(s)/Patent Under Reexamination
10584334	SHIN ET AL.
Examiner	Art Unit
JULIO PEREZ	2617

SEARCHED				
Class	Subclass	Date	Examiner	
455	423, 37.11	5/7/2010	JP	
Updated search		11/27/2010	JP	
455	446, 453	11/27/2010	JP	
455	423, 67.1, 67.2, 67.4	5/31/2011	JP	

SEARCH NOTES		
Search Notes	Date	Examiner
East (text search)	5/7/2010	JP
Inventor's search	5/7/2010	JP
Inventor's search	11/27/2010	JP
Consulted Wayne Cai	5/31/2011	JP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/J. P./ Examiner.Art Unit 2617	

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